



UNIVERSITÀ DEGLI STUDI
DI TRENTO



The 6th International Conference on
Crack Paths (CP 2018)

Crack path and notch fatigue strength of Ti-6Al-4V ELI additively manufactured via selective laser melting: Defect sensitivity

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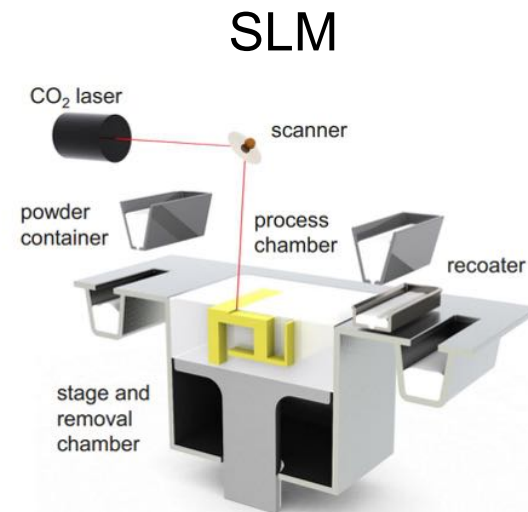
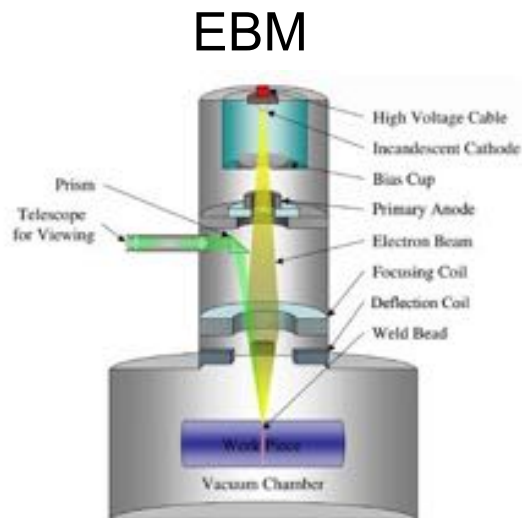
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Verona, Italy, September 19th, 2018

Additive manufacturing of metal parts

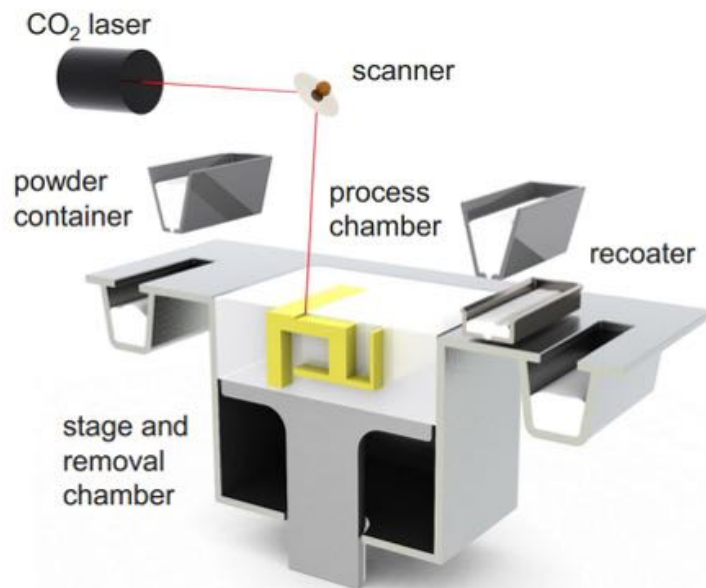
- Net-shape production technologies
- Solid object from the sequential superposition of layers.
- The most common AM processes for metals are selective laser melting (SLM) and electron beam melting (EBM).



- SLM is well suited to additively manufacture small-to-medium amounts of parts with moderate-to-high surface finish.

The SLM process

- From a rapid prototyping technique to a rapid manufacturing process.
- It can be applied to many different powders but for many mechanical and biomedical applications the most interesting materials are Ti-6Al-4V (Grade 5) and Ti-6Al4V ELI (Grade 23).



Defects in SLM components that can affect the fatigue life:

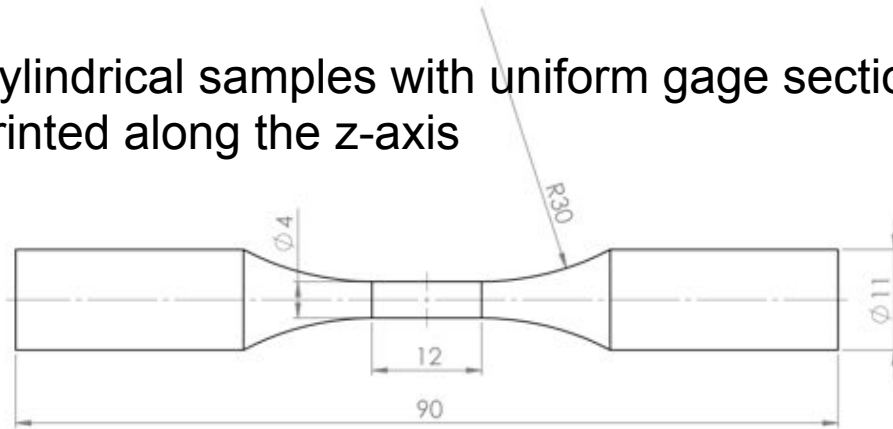
- ✓ Residual stresses due to the melting and solidification process
- ✓ Internal porosity
- ✓ Surface roughness due to the presence of partially sintered particles
- ✓ Oxide layer that can be formed during the stress relief heat treatment

Aim and motivation

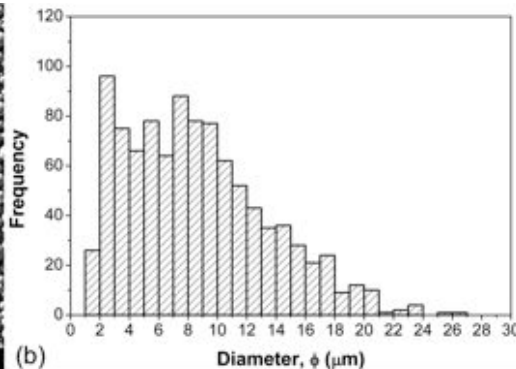
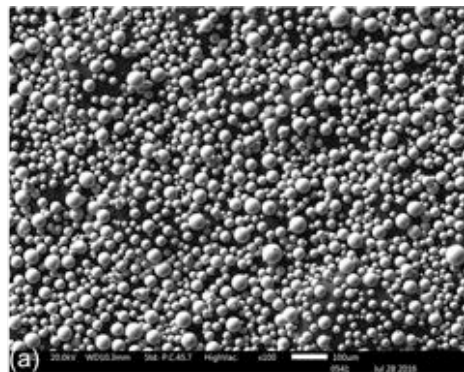
- Investigation of the fatigue properties of the biomedical Ti Grade 23 manufactured via SLM.
- Quantitative assessment of the effect of selected post processing treatments on the fatigue response.
- Fatigue tests carried out at different R -ratios and microstructural conditions.
- Material characterization complemented with computed tomography (CT) scans, metallographic and fractographic analyses.
- Analysis of **defect sensitivity**.
- **Notch effect and defects: is TCD a viable fatigue calculation approach?**

Specimens preparation

Cylindrical samples with uniform gage section printed along the z-axis



Atomized powder of biomedical Titanium Grade 23



Mean powder diameter: $\approx 9 \mu\text{m}$

3D System ProX DMP 300

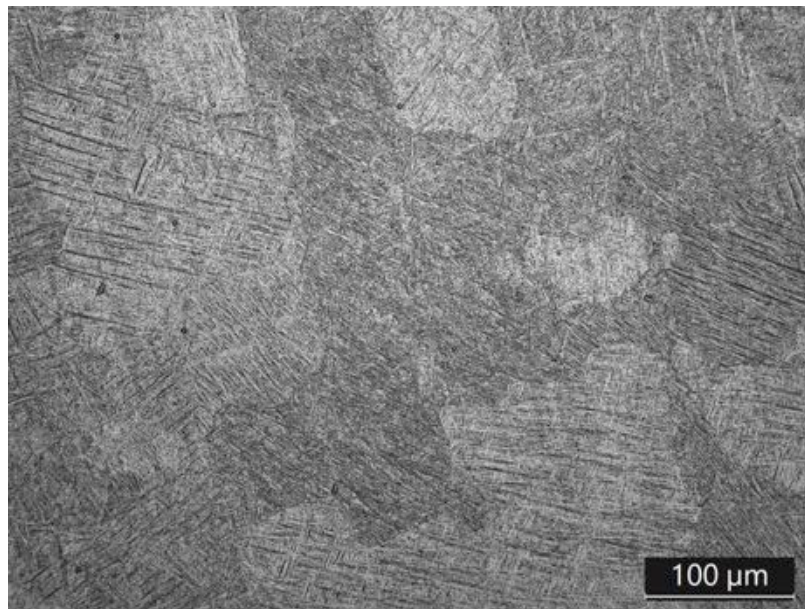
Build Envelope Capacity	250 x 250 x 300 mm
Layer thickness	5 ÷ 100 μm
Repeatability	x = y = z = 20 μm
Min. feature size	x = 100 μm , y = 100 μm , z = 20 μm
Min. wall thickness	150 μm
Accuracy	$\pm 0,1\%-0,2\%$ with $\pm 50 \mu\text{m}$

“As-built” specimens

Low-temperature stress relief
(5h @ 670°C, Ar)



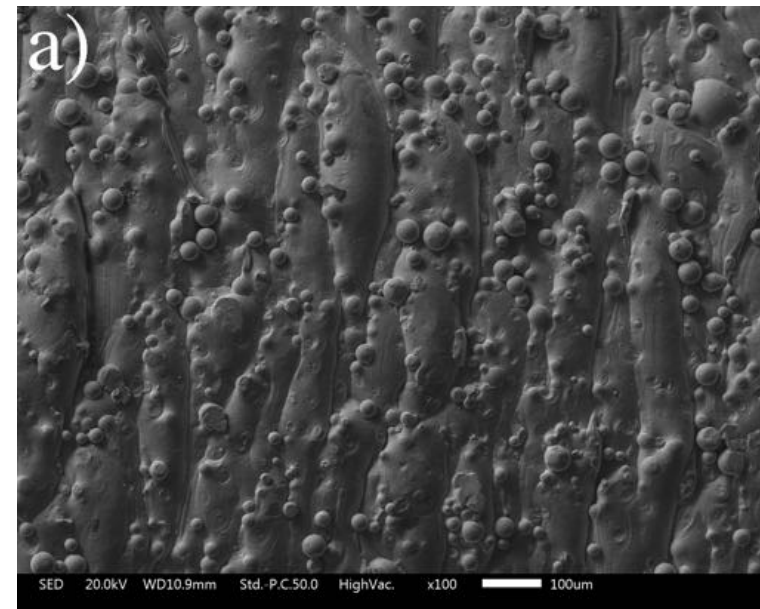
Fine acicular α' martensite



Surface finish not altered by post-processing treatments



Surface striations + unmolten powder particles (Ra 6.8 μm)



Fatigue tests



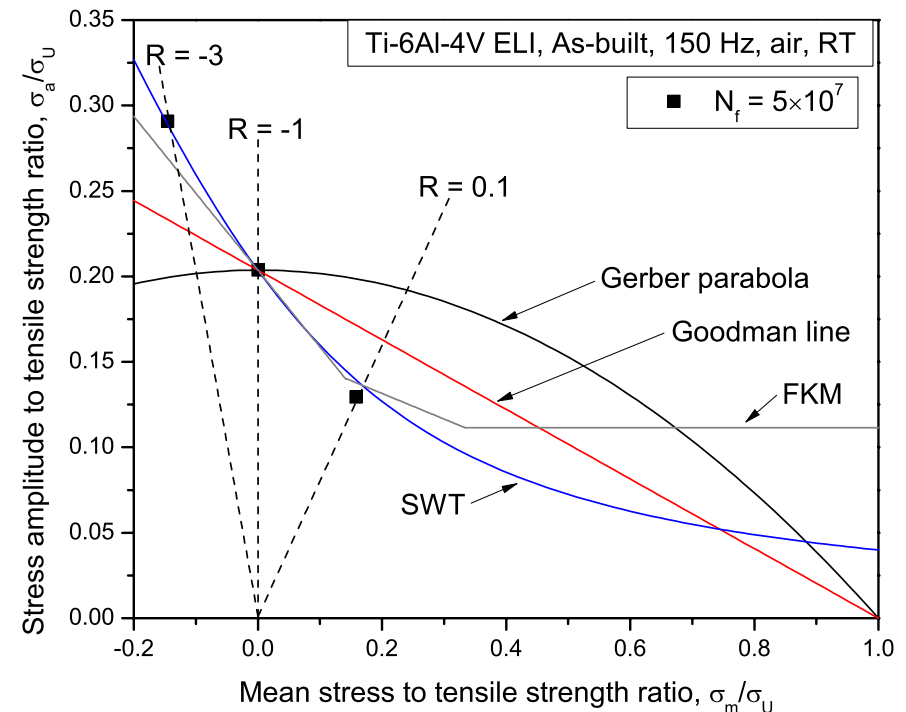
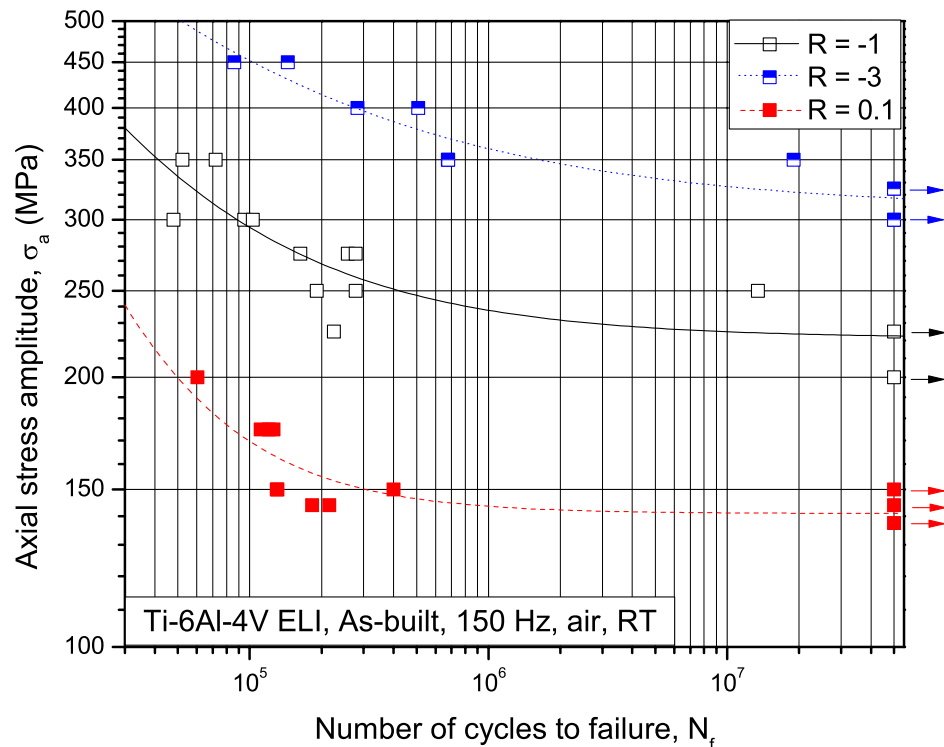
- Load controlled axial fatigue tests
- 150 Hz, laboratory environment
- Load ratios $R = -1$, $R = -3$ and $R = 0.1$
- Explored fatigue lives: between 5×10^4 and 5×10^7 cycles

Computed tomography (CT) scans



- Metrological X-ray CT system Nikon X-Tek MCT225
- Central part of the gage length analyzed with volume of $\approx 40 \text{ mm}^3$
- Detection of pores in terms of volume, projected area and min. distance from the outer surface

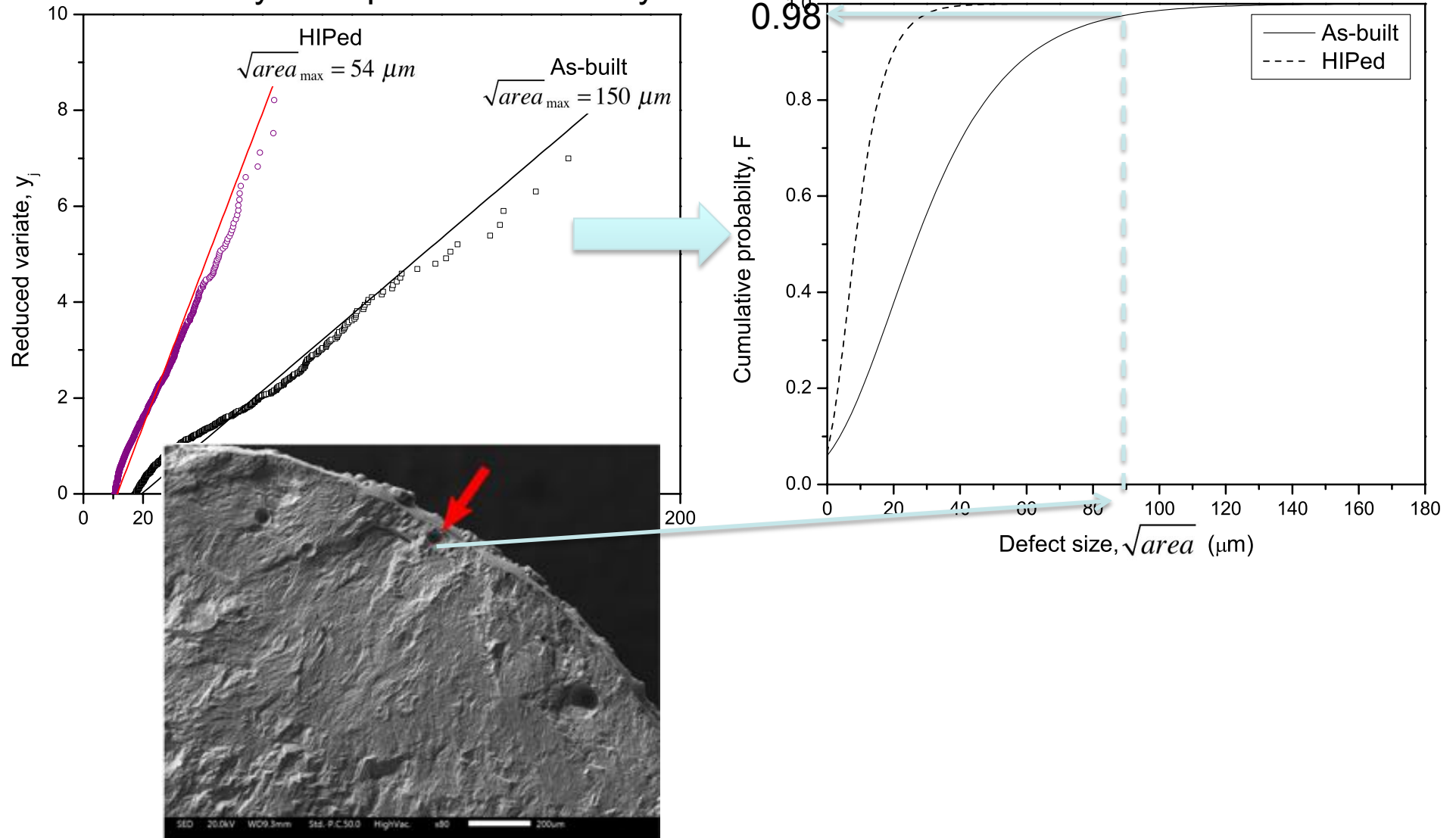
Fatigue tests: mean stress sensitivity



- Low fatigue properties of the as-built condition (20% of UTS)
- Marked mean stress sensitivity, not captured by classical approaches
- Tensile mean stresses are particularly detrimental, while compressive mean stresses induces a remarkable increment in the fatigue strength
- Fatigue strength dictated both by mean and maximum stress

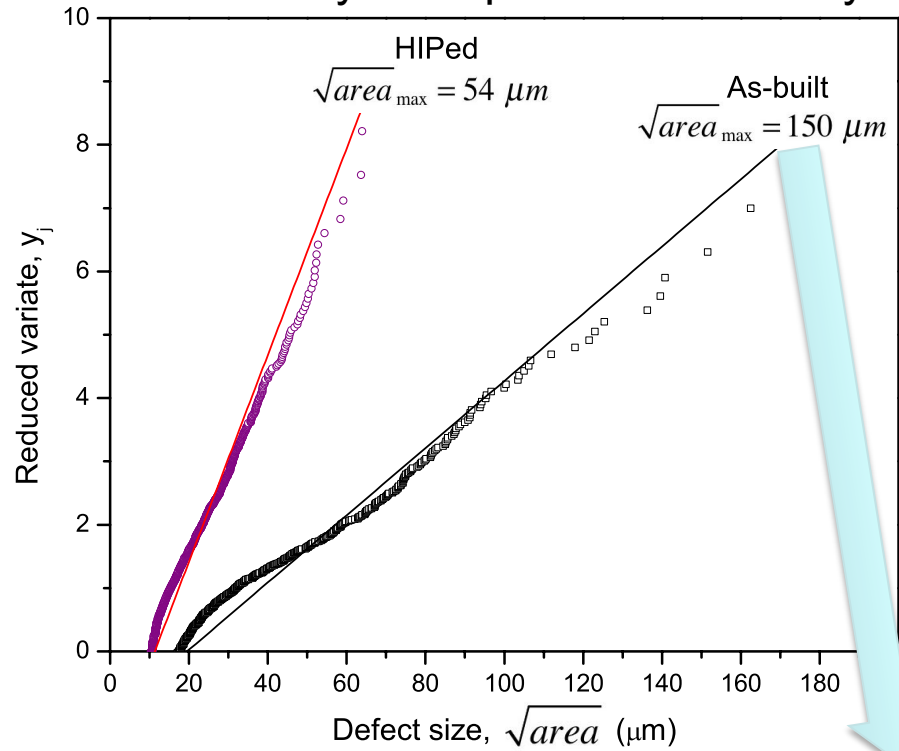
Pore size effect on fatigue

Statistical analysis of pores detected by CT

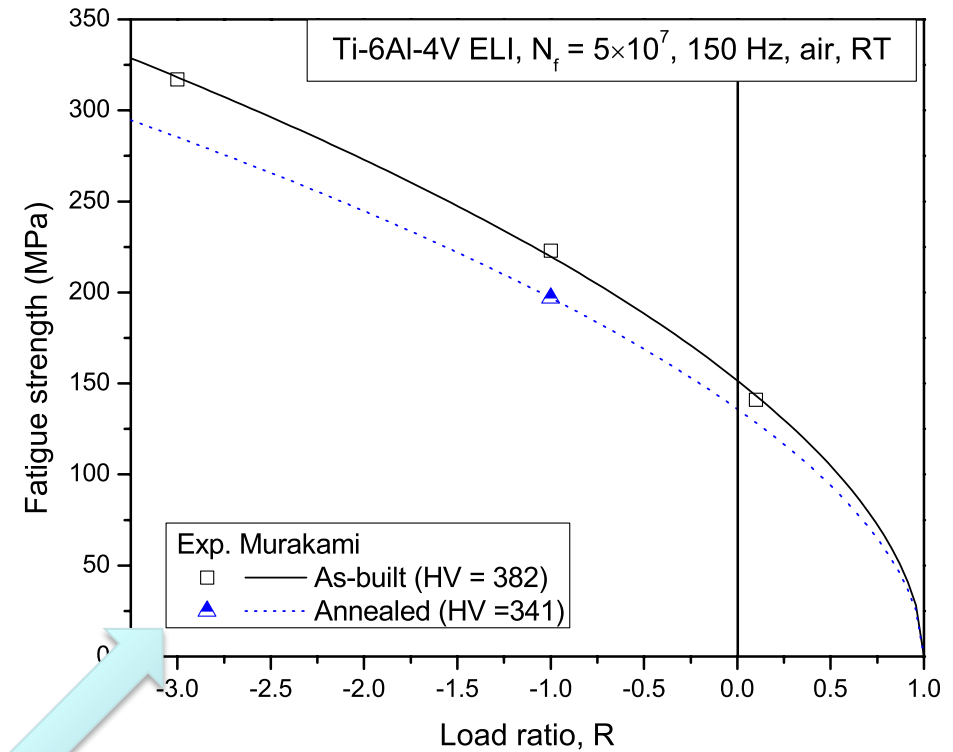


Pore size effect on fatigue

Statistical analysis of pores detected by CT



Murakami model calibration



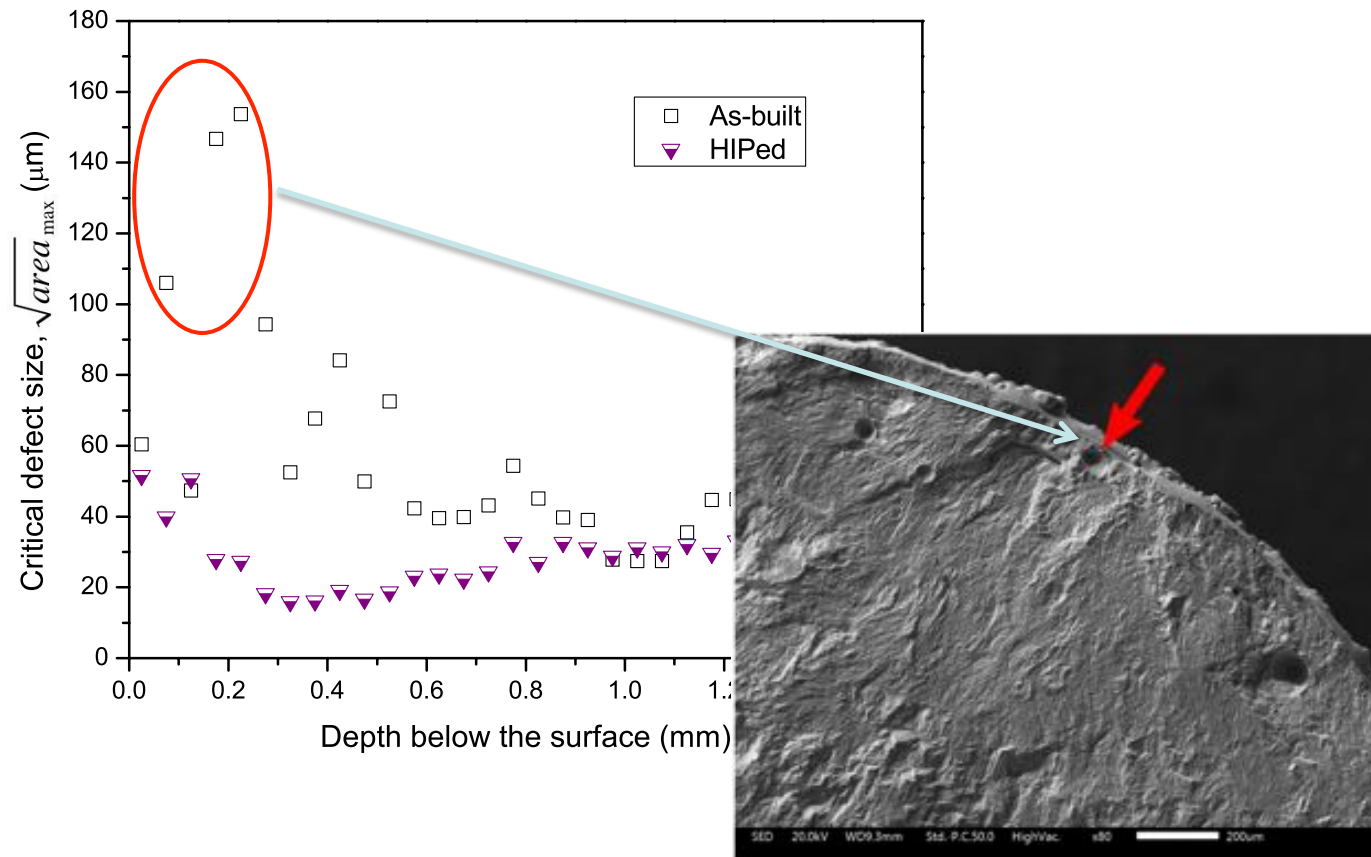
Murakami model

$$\sigma_w = \frac{F_{Loc} F_{HV}}{(\sqrt{area}_{max})^{1/6}} \left(\frac{1-R}{2} \right)^m$$

$$F_{HV} = a \cdot HV + b$$

$$F_{Loc} = \begin{cases} 1.43 & \text{Surface defect} \\ 1.41 & \text{Near surface defect} \\ 1.56 & \text{Internal defect} \end{cases}$$

Critical pore size as a function of depth¹

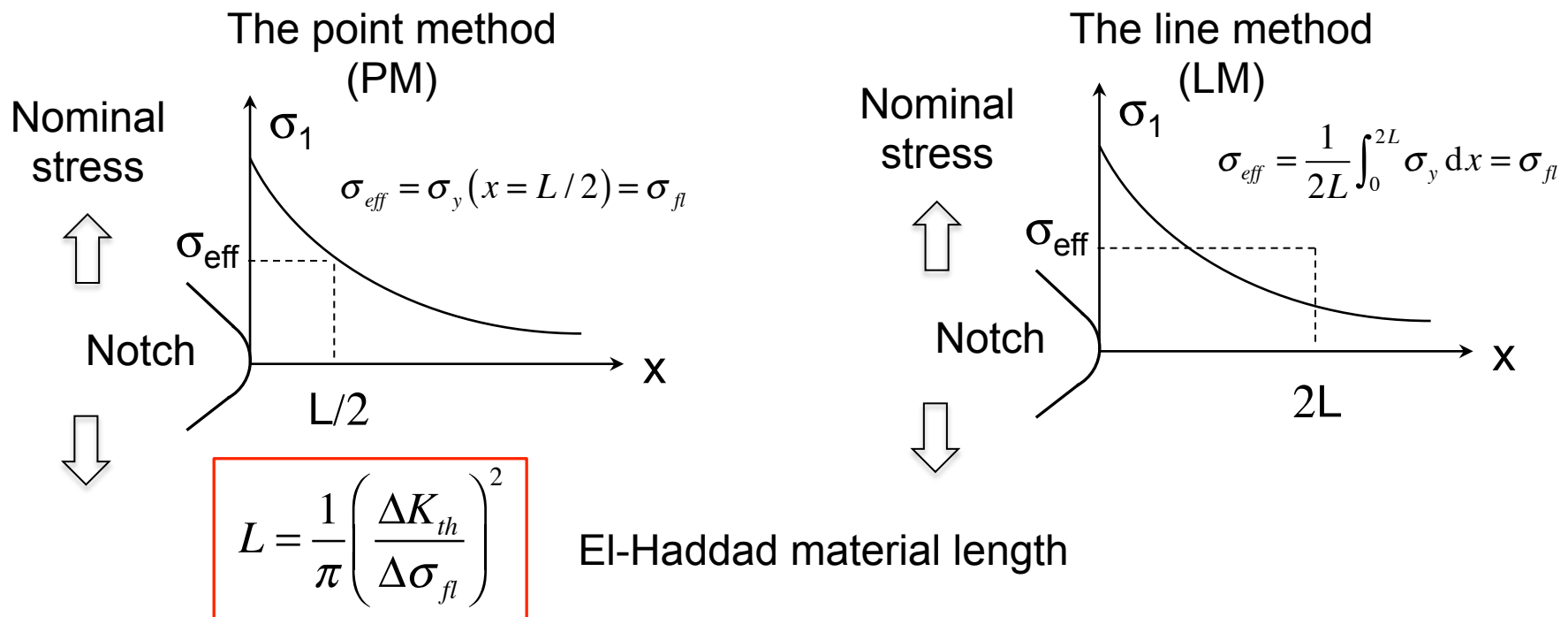


¹ M. Benedetti et al., Int. J. Fatigue, 2018;107:96-109.

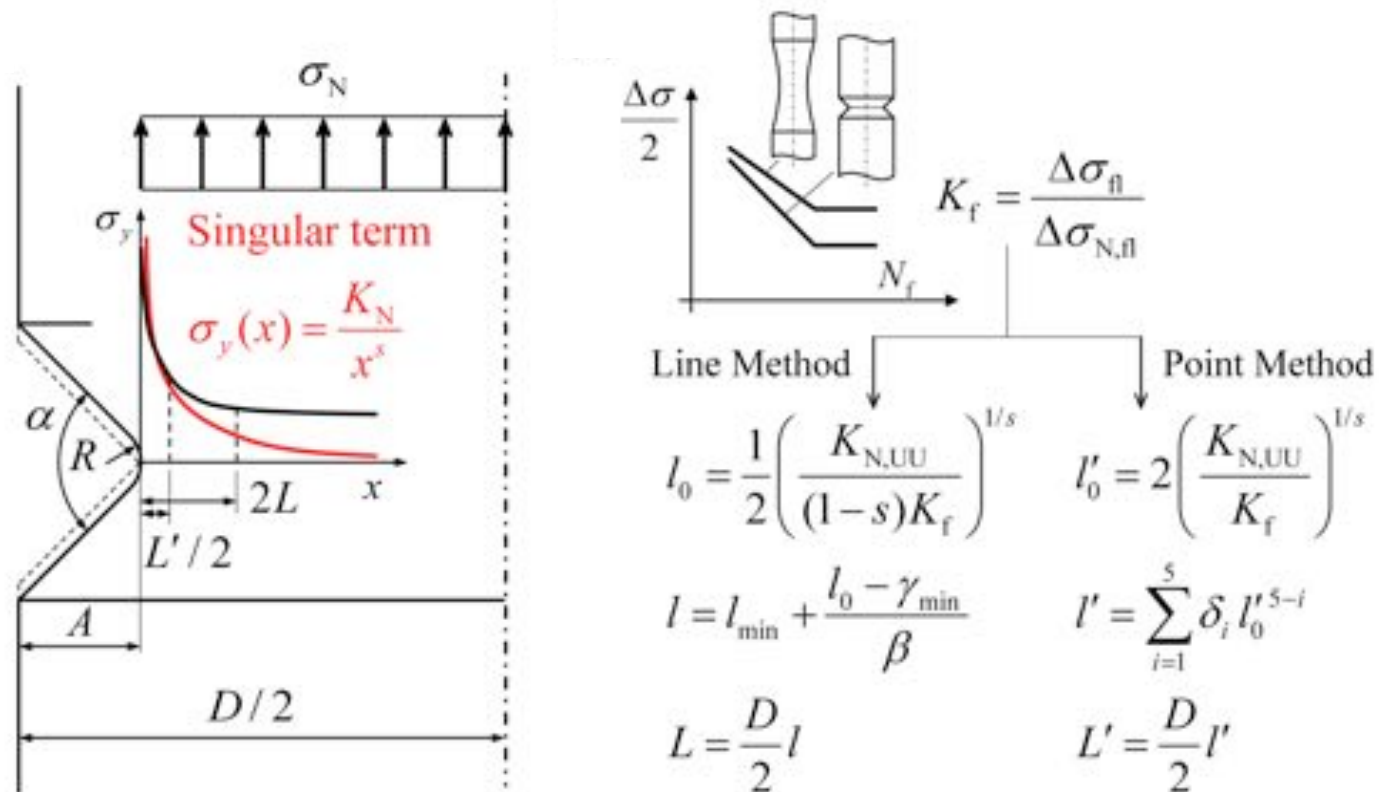
Notch fatigue strength of AMed materials: an open issue

- How does the **concomitant** presence of **notch** effects and **defectiveness** influences the fatigue strength?
- This is of paramount importance, as AM components usually display **intricate** geometry resulting in severe stress concentration effects and therefore necessitate **robust notch** fatigue assessment methods.

The theory of critical distance (TCD)



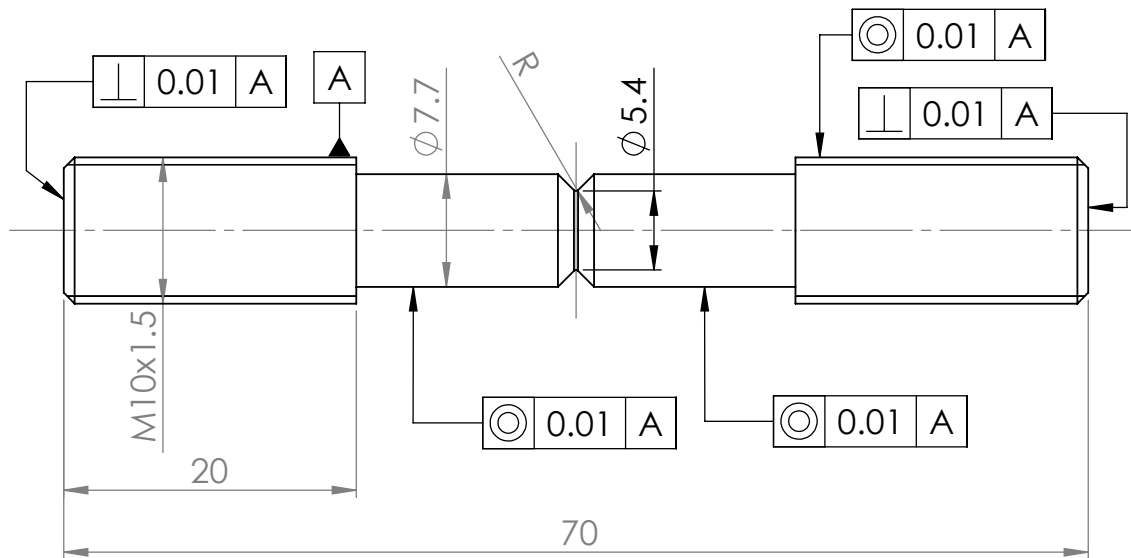
Alternative critical distance determination^{1,2}



¹ C. Santus et al., Int. J. Fatigue, 2018;106:208-218.

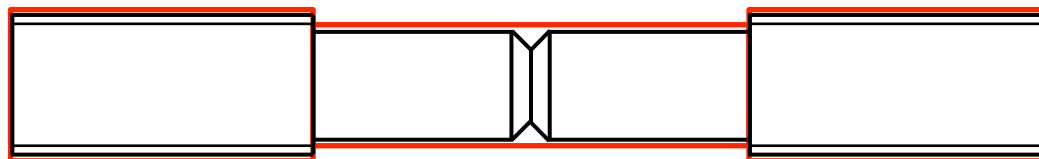
² C. Santus et al., Int. J. Fatigue, 2018;113:113-125.

Notched specimens

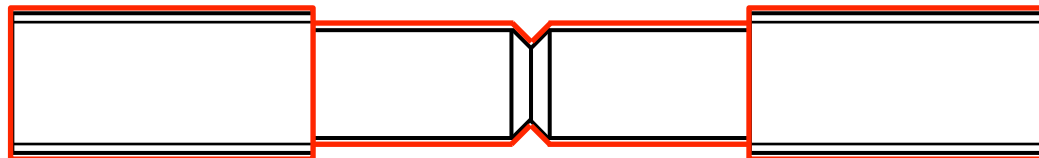


Notch root radius R:

- **R0.2: sharp notch**
- **R1: blunt notch**

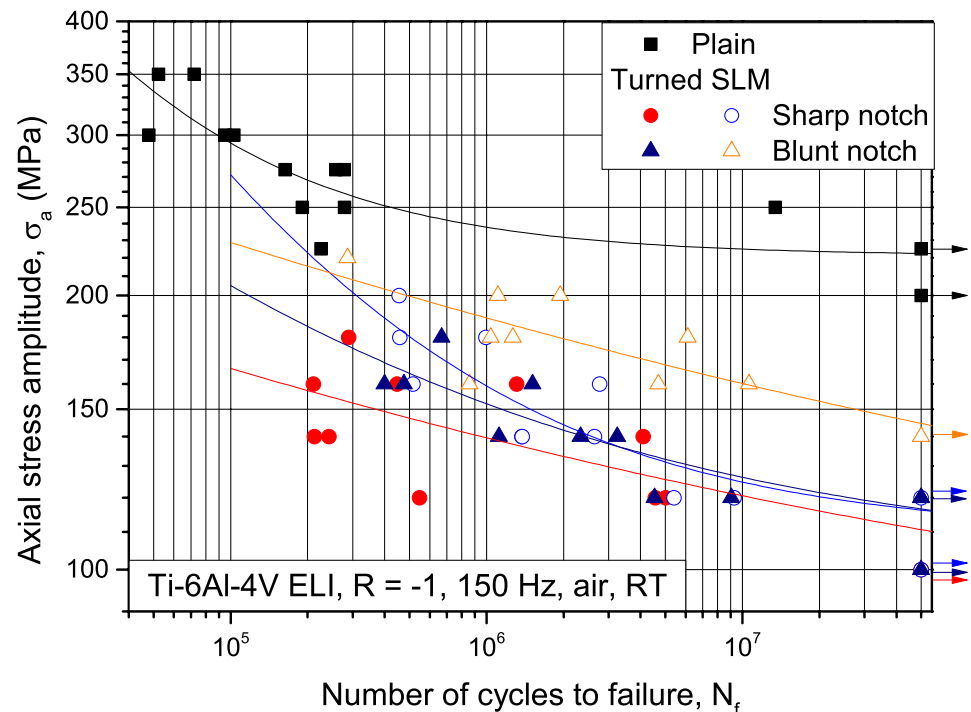


Turned notch



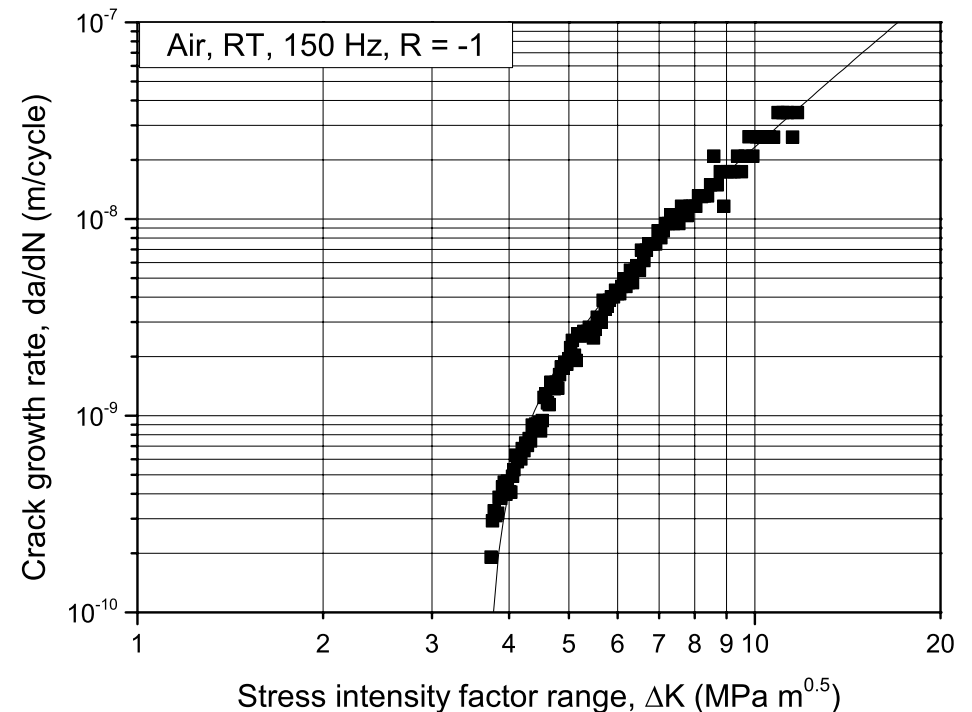
SLM notch

SN curves



- Fatigue strength of Turned-notched (solid symbols) is lower than that of the SLM-notched (open symbols) variant.
- Large scatter.

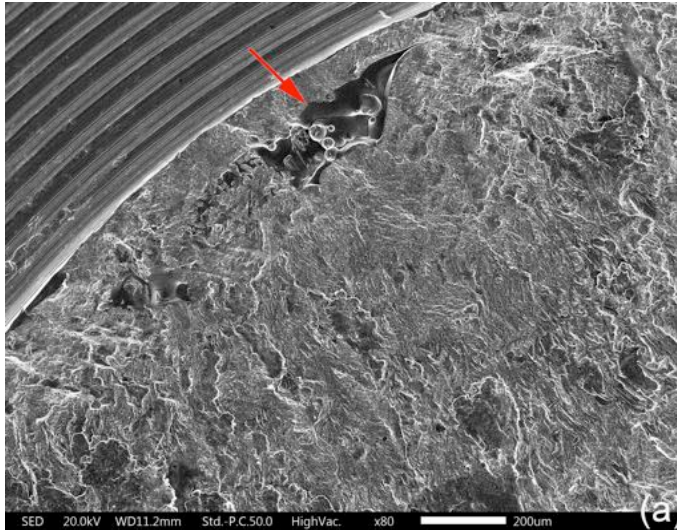
da/dN-ΔK curves



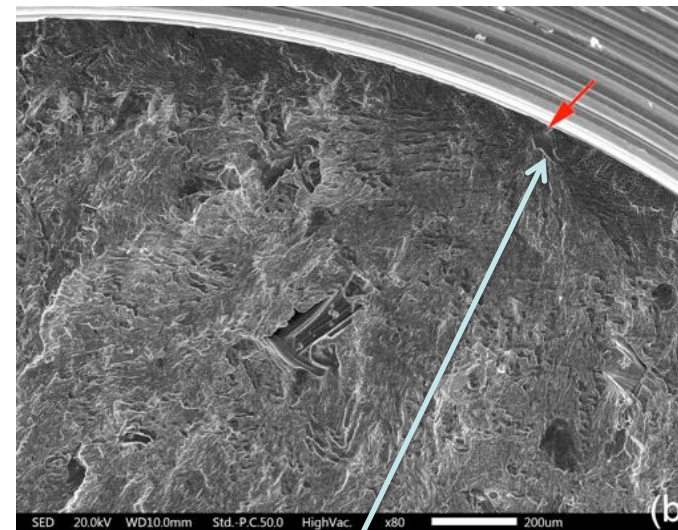
- Low FCG resistance as a consequence of the fine martensitic microstructure.
- $\Delta K_{th} = 3.7 \text{ MPa m}^{0.5}$

SEM fractographic analysis

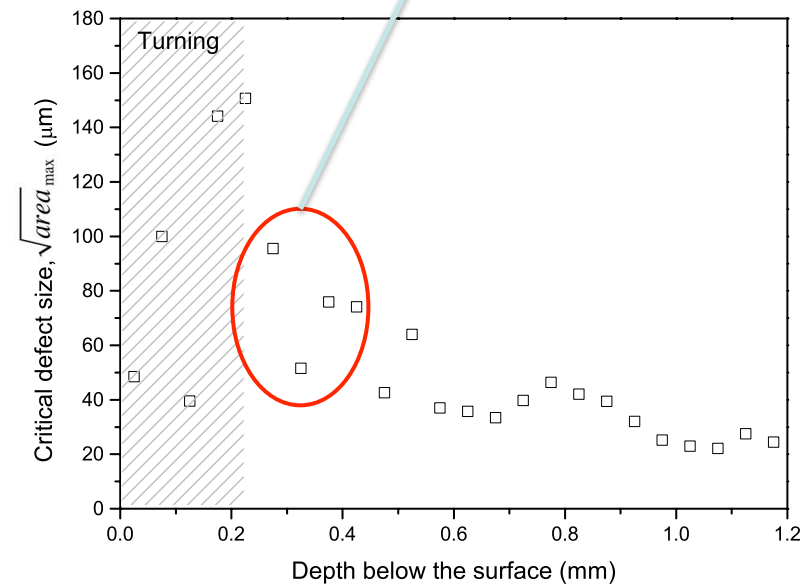
Turned notch



SLM notch



- Crack initiation starts from a defect in the immediate vicinity of the notch tip.
- Critical defect is larger in the turned than in the SLM-notch.
- Sample batches with different size of defects ahead of the notch

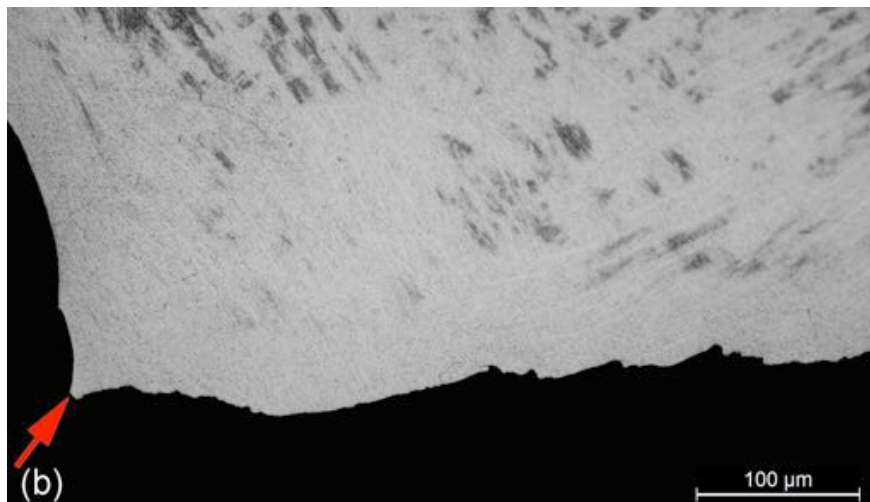


Crack path from crack initiation site

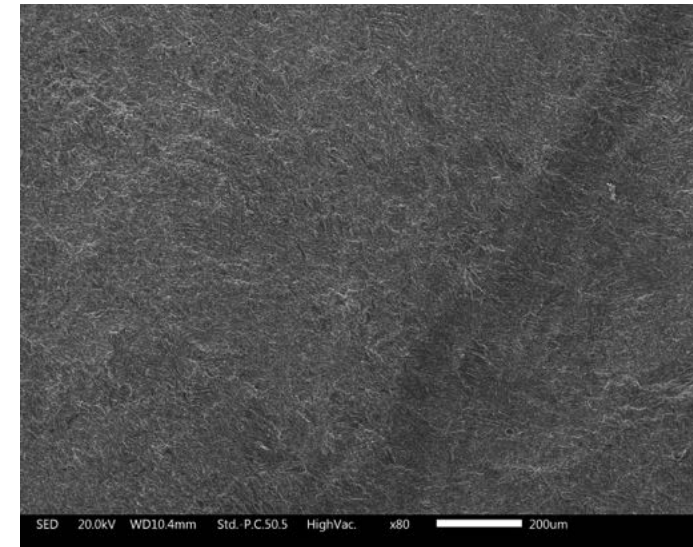
Turned notch



SLM notch



M(T) specimen



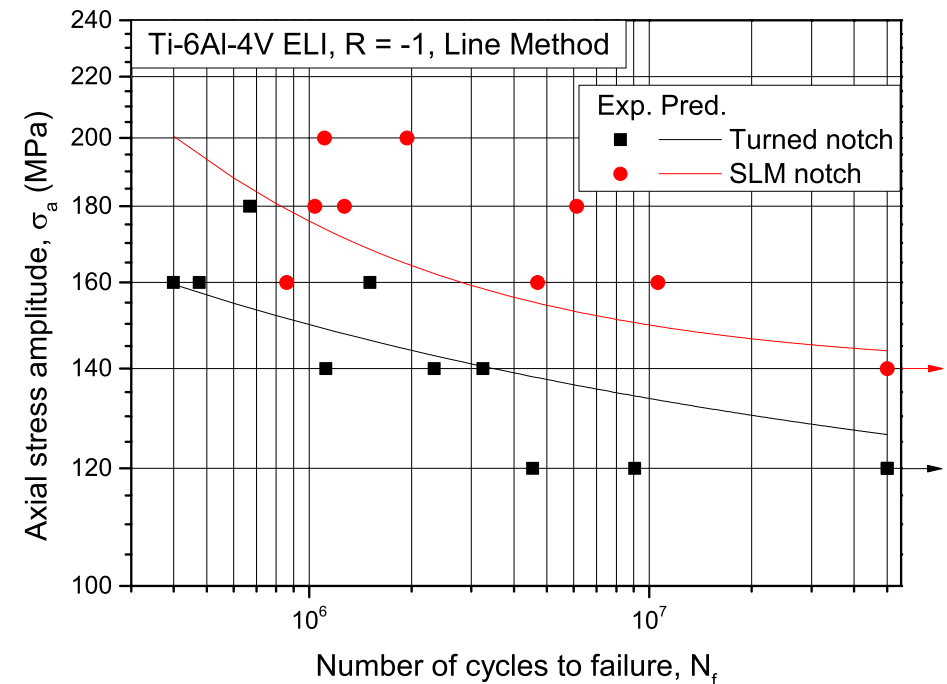
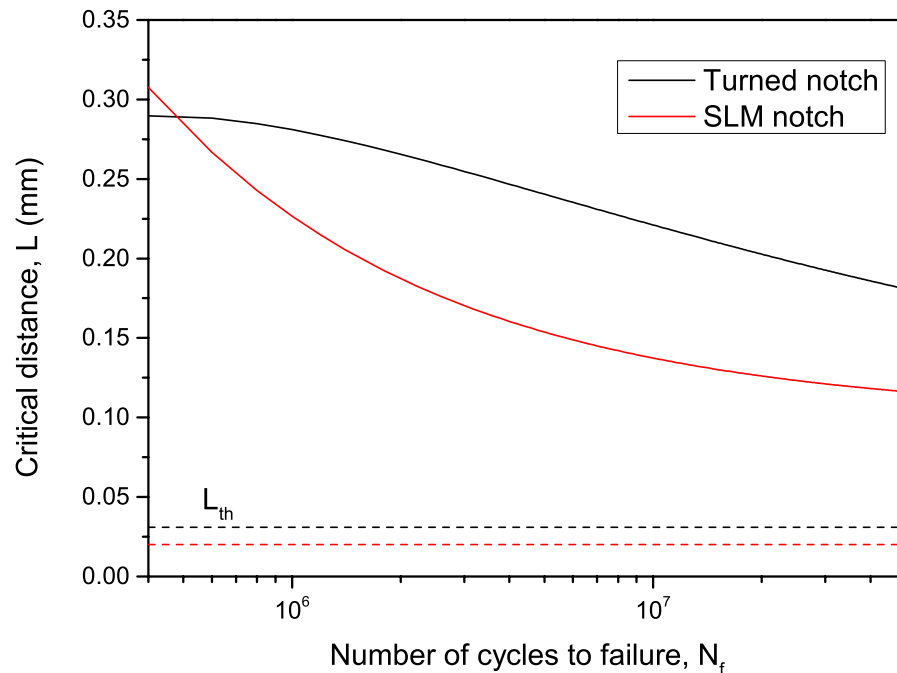
- The early crack propagation stage is approximately **straight** and fairly **orthogonal** to the loading direction.
- Subsequently, the crack exhibits, an **erratic** zigzagging path to **interconnect** the **nearest** defects encountered during its propagation.

TCD predictions

Sample geometry	Critical defect size \sqrt{area} (μm)	σ_w (MPa)	K_f	L (mm)	L' (mm)	L_{th} (mm)
Plain	150	225	-	-	-	
Turned sharp notch	210	190	1.73	0.180	0.260	0.031
SLM sharp notch	60	230	1.98	0.115	0.180	0.020

Sample geometry	Fatigue strength @ 5×10^7 cycles (MPa)								
	Exp.	L, L' from Sharp notch				L_{th} from M(I)			
		LM		PM		LM		PM	
		Pred.	Err. (%)	Pred.	Err. (%)	Pred.	Err. (%)	Pred.	Err. (%)
Turned blunt notch	116.6	125.9	8.0	119.9	2.8	100.9	-13.5	97.9	-16.0
SLM blunt notch	144.8	143.5	-0.9	139.3	-3.8	122.4	-15.5	119.9	-17.2

TCD predictions: medium-to-high cycle fatigue



- Critical length decreases with increasing fatigue life N_f .
- L derived from sharp notched samples is 3-4 times larger than L_{th} and depends upon material defectiveness.
- Accurate predictions of the blunt-notched samples, also in view of the large scatter of the experimental data.

1. Fatigue properties of Ti64 additively manufactured via SLM are mainly dictated by defectiveness.
2. Defectiveness sensitivity is well represented by the Murakami \sqrt{area} model.
3. Notch fatigue strength is controlled by the largest defect in the immediate vicinity of the notch root.
4. Large scatter in notch fatigue results.
5. The size of the critical defects strongly depends upon the notch-manufacturing route (SLM vs. turned notch!).
6. The critical distance length increases with increasing size of the critical defect.
7. Defectiveness influences much the crack path of micro-cracks, little that of macro-cracks. Fracture mechanics tests not indicated for determining L.
8. Accurate prediction obtained by TCD in combination with the proposed critical distance inverse search procedure, especially if the actual defectiveness of the sample is known.



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THANK YOU FOR YOUR ATTENTION!

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Verona, Italy, September 19th, 2018